

Notice of References Cited	Application/Control No. 10/624,733	Applicant(s)/Patent Under Reexamination KOBASHIKAWA ET AL.	
	Examiner Shew-Fen Lin	Art Unit 2166	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0037114 A1	02-2003	Nishio et al.	709/206
*	B	US-2003/0078981 A1	04-2003	Harms et al.	709/206
*	C	US-6,564,264 B1	05-2003	Creswell et al.	709/245
*	D	US-2003/0097361 A1	05-2003	HUANG et al.	707/10
*	E	US-2003/0158793 A1	08-2003	Takakura et al.	705/27
*	F	US-2004/0059784 A1	03-2004	Caughey, David A.	709/206
*	G	US-6,895,426 B1	05-2005	Cortright et al.	709/206
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.